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H. Kubátová, CTU in Prague (CZ)

**SPECIAL SESSION PROGRAM
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Y. Zorian, Virage Logic, CA (US)

CONTACT INFORMATION

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**SPECIAL SESSION ON DEPENDABILITY AND TESTING OF DIGITAL SYSTEMS
(DTDS)**

Every designed system has to be tested several times during its life period - during its design, production and its functionality. The need for testing strictly depends on the actual use of the system, e.g., if the system can be repaired or not, if the system must be safe, etc. The design must reflect these requirements. The special session on "Dependability and Testing of Digital Systems" (DTDS) addresses emerging issues, hot problems, new solution methods and their hardware and software implementations in all fields of digital and mixed-signal system dependability and testing. It is especially focused on the dependability and testing related to the SoC technology and modern embedded applications:

SPECIAL SESSION SCOPE

Papers on any of the following and related topics can be submitted to the special session:

- Built-in Self-Test: off-line BIST and on-line BIST
- SoC and NoC Testing
- Error Detection and Correction
- Test Compression Methods
- Testability Analysis
- Scan-based techniques
- IDDQ and Current Testing
- Synthesis for Testability
- Diagnosis & Testing of Embedded Systems
- Analog, Mixed-Signal and RF Testing
- Memory and Processor Testing
- System Diagnosis

SUBMISSION GUIDELINES

Prospective authors are encouraged to submit their manuscripts for review electronically through the following web page (<http://www.easychair.org/conferences/?conf=dsd2012>) or by sending the paper to the Session Chair via email (kubatova@fit.cvut.cz) only if an unexpected web access problem is encountered) before the deadline for submission.

Each manuscript should include the complete paper text, all illustrations, and references. The manuscript should conform to the required IEEE format: single-spaced, double column, A4/US letter page size, 10-point size Times Roman font, up to 8 pages. In order to conduct a blind review, no indication of the authors' names should appear in the submitted manuscript, references included.

The IEEE Conference Publishing Services (CPS), Conference Publishing Services, publishes the DSD Proceedings, which are available worldwide through the IEEE Xplore Digital Library. An extended version of the best papers will be published in a special issue of the ISI-indexed "Microprocessors and Microsystems: Embedded Hardware Design" journal, printed by Elsevier Ltd.

IMPORTANT DATES

- **Submission of papers: March 26th, 2012**
- Notification of acceptance: May 7th, 2012
- Camera ready papers: May 31st, 2012
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WEB LINKS

- DSD'12 web page:
- www.univ-valenciennes.fr/dsd2012/
- Euromicro web page:
<http://www.euromicro.org>